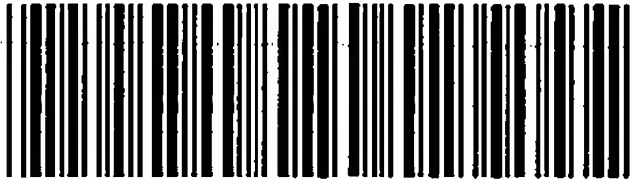


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/645,412	HON ET AL.	
	Examiner	Art Unit	
	Patricia Leith	1655	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
updated EAST:JPO,EPO,DERWENT,USPATF ULL,USPGPUBS,OCRBACKFILE	2/2/2006	PL